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| <b>Search Notes</b><br><br> | <b>Application/Control No.</b><br><br>09965030 | <b>Applicant(s)/Patent Under Reexamination</b><br><br>NIWA ET AL. |
|  | <b>Examiner</b><br><br>Shin, Kyung H           | <b>Art Unit</b><br><br>2143                                       |

| SEARCHED |               |         |          |
|----------|---------------|---------|----------|
| Class    | Subclass      | Date    | Examiner |
| 709      | 238, 249, 230 | 8/17/07 | KHS      |
| 710      | 305, 306      | 8/17/07 | KHS      |
| 370      | 392, 463, 466 | 8/17/07 | KHS      |

| SEARCH NOTES                        |         |          |
|-------------------------------------|---------|----------|
| Search Notes                        | Date    | Examiner |
| Search Rpt. included                | 8/17/07 | KHS      |
| IEEE, NPL, Google search            | 8/17/07 | KHS      |
| Consulted with PWU, JEFFREY C (SPE) | 8/16/07 | KHS      |

| INTERFERENCE SEARCH |               |         |          |
|---------------------|---------------|---------|----------|
| Class               | Subclass      | Date    | Examiner |
| 710                 | 305, 306      | 8/17/07 | KHS      |
| 370                 | 392, 463, 466 | 8/17/07 | KHS      |